

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re Application of Applicants:

Date: February 27, 2008

Beaman et al.

Group Art Unit: 2829

Serial No.: 09/251,988

Examiner: J. M. Hollington

Filed: February 17, 1999

Docket No.: YOR91999088US1

For: STRUCTURAL DESIGN AND PROCESSES TO CONTROL PROBE  
POSITION ACCURACY IN A WAFER TEST PROBE ASSEMBLY

Amendment AF  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

In response to the Office Action dated December 21, 2008, please  
consider the following: